Emile Albert Schweikert

List of Publications by Year in descending order

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220 papers

3,058 citations

279487 23 h-index 253896 43 g-index

229 all docs

229 docs citations

times ranked

229

2126 citing authors

#	Article	IF	CITATIONS
1	Calcium Phosphate Phase Identification Using XPS and Time-of-Flight Cluster SIMS. Analytical Chemistry, 1999, 71, 149-153.	3.2	191
2	Impact of slow gold clusters on various solids: nonlinear effects in secondary ion emission. Nuclear Instruments & Methods in Physics Research B, 1991, 62, 8-22.	0.6	174
3	The influence of surface chemistry on the kinetics and thermodynamics of bacterial adhesion. Scientific Reports, 2018, 8, 17247.	1.6	124
4	Secondary-ion yields from surfaces bombarded with keV molecular and cluster ions. Physical Review Letters, 1989, 63, 1625-1628.	2.9	121
5	Nanoscopic Cylindrical Dual Concentric and Lengthwise Block Brush Terpolymers as Covalent Preassembled High-Resolution and High-Sensitivity Negative-Tone Photoresist Materials. Journal of the American Chemical Society, 2013, 135, 4203-4206.	6.6	104
6	Coincidence Counting in Time-of-Flight Mass Spectrometry: A Test for Chemical Microhomogeneity. Science, 1990, 248, 988-990.	6.0	57
7	Charged particle activation of medium Z elements. Journal of Radioanalytical Chemistry, 1976, 31, 437-450.	0.5	53
8	Micropatterning of Proteins and Mammalian Cells on Indium Tin Oxide. ACS Applied Materials & Samp; Interfaces, 2009, 1, 2592-2601.	4.0	52
9	Noradrenaline-Functionalized Hyperbranched Fluoropolymer–Poly(ethylene glycol) Cross-Linked Networks As Dual-Mode, Anti-Biofouling Coatings. ACS Nano, 2012, 6, 1503-1512.	7.3	52
10	Kiloelectron volt cluster impacts: prospects for cluster-SIMS. International Journal of Mass Spectrometry and Ion Processes, 1998, 174, 167-177.	1.9	48
11	Solidâ^'Liquid Adsorption of Calcium Phosphate on TiO2. Langmuir, 1999, 15, 7355-7360.	1.6	45
12	Exercising Spatiotemporal Control of Cell Attachment with Optically Transparent Microelectrodes. Langmuir, 2008, 24, 6837-6844.	1.6	40
13	Ultratrace determination of oxygen and carbon by charged particle activation analysis. Analytical Chemistry, 1969, 41, 958-963.	3.2	36
14	Nondestructive determination of some trace elements in tantalum by proton activation analysis. Analytical Chemistry, 1974, 46, 1626-1629.	3.2	36
15	Targeted surface nanocomplexity: two-dimensional control over the composition, physical properties and anti-biofouling performance of hyperbranched fluoropolymer–poly(ethylene glycol) amphiphilic crosslinked networks. Polymer Chemistry, 2012, 3, 3121.	1.9	36
16	Methodology and application of the nuclear resonance reaction $160(\hat{l}\pm,\hat{l}\pm)160$ for the profiling of titanium oxide. Nuclear Instruments & Methods in Physics Research B, 1988, 35, 159-166.	0.6	34
17	Effectiveness of atomic and polyatomic primary ions for organic secondary ion mass spectrometry. International Journal of Mass Spectrometry, 2001, 207, 111-122.	0.7	28
18	Single Impacts of C ₆₀ on Solids: Emission of Electrons, lons and Prospects for Surface Mapping. Journal of Physical Chemistry C, 2010, 114, 5637-5644.	1.5	27

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19	Analysis of Native Biological Surfaces Using a 100 kV Massive Gold Cluster Source. Analytical Chemistry, 2011, 83, 8448-8453.	3.2	27
20	Determination of lithium, boron, and carbon by quasi-prompt charged particle activation analysis. Analytical Chemistry, 1975, 47, 2403-2407.	3.2	26
21	Secondary ion yields produced by keV atomic and polyatomic ion impacts on a self-assembled monolayer surface., 1999, 13, 1374-1380.		26
22	Characterization and quantification of nanoparticle–antibody conjugates on cells using C60 ToF SIMS in the event-by-event bombardment/detection mode. International Journal of Mass Spectrometry, 2011, 303, 97-102.	0.7	25
23	Preventing adhesion of Escherichia coli O157:H7 and Salmonella Typhimurium LT2 on tomato surfaces via ultrathin polyethylene glycol film. International Journal of Food Microbiology, 2014, 185, 73-81.	2.1	25
24	Nondestructive charged particle activation analysis using short-lived nuclides. Analytical Chemistry, 1972, 44, 1386-1391.	3.2	24
25	Comparison of nondestructive proton and neutron activation: The case of biological samples. Journal of Radioanalytical Chemistry, 1977, 37, 571-580.	0.5	24
26	The use of glass substrates with bi-functional silanes for designing micropatterned cell-secreted cytokine immunoassays. Biomaterials, 2011, 32, 5478-5488.	5.7	24
27	Hydrogen and deuterium analysis by heavy ion activation. Journal of Radioanalytical Chemistry, 1977, 37, 275-283.	0.5	23
28	Compact timeâ€ofâ€flight mass spectrometer using particleâ€induced desorption. Review of Scientific Instruments, 1986, 57, 692-694.	0.6	23
29	Surface characterization with keV clusters and MeV ions. Nuclear Instruments & Methods in Physics Research B, 1990, 50, 307-313.	0.6	22
30	Nanovolume Analysis with Secondary Ion Mass Spectrometry Using Massive Projectiles. Analytical Chemistry, 2006, 78, 7410-7416.	3.2	22
31	Secondary ion mass spectrometry with C60+ and Au4004+ projectiles: Depth and nature of secondary ion emission from multilayer assemblies. International Journal of Mass Spectrometry, 2008, 269, 112-117.	0.7	22
32	Determination of oxygen in silicon in the sub-part-per-million range by charged-particle activation analysis. Analytical Chemistry, 1970, 42, 1525-1527.	3.2	21
33	Matrix-enhanced cluster-SIMS. Applied Surface Science, 2006, 252, 6624-6627.	3.1	21
34	Characterization of Individual Nano-Objects by Secondary Ion Mass Spectrometry. Analytical Chemistry, 2008, 80, 9052-9057.	3.2	21
35	The Pegase project, a new solid surface probe: focused massive cluster ion beams. Surface and Interface Analysis, 2011, 43, 66-69.	0.8	21
36	Chemical etching procedure used to remove surface oxygen contamination in charged-particle activation analysis. Analytical Chemistry, 1968, 40, 1194-1196.	3.2	20

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37	Time-of-flight-secondary ion mass spectrometry of NaBF4: a comparison of atomic and polyatomic primary ions at constant impact energy. Rapid Communications in Mass Spectrometry, 1997, 11, 1794-1798.	0.7	20
38	Multi-ion emission from large and massive keV cluster impacts. International Journal of Mass Spectrometry, 2005, 245, 48-52.	0.7	20
39	Characterization of Individual Ag Nanoparticles and Their Chemical Environment. Analytical Chemistry, 2009, 81, 1089-1094.	3.2	20
40	Directing Selfâ€Assembly of Nanoscopic Cylindrical Diblock Brush Terpolymers into Films with Desired Spatial Orientations: Expansion of Chemical Composition Scope. Macromolecular Rapid Communications, 2014, 35, 437-441.	2.0	20
41	Multielement charged particle activation analysis with x-ray counting. Analytical Chemistry, 1976, 48, 429-435.	3.2	19
42	Analysis of polystyrene/PVME blends by coincidence counting time-of-flight mass spectrometry. Analytical Chemistry, 1992, 64, 843-847.	3.2	18
43	Size-dependent emission of negative ions from gold nanoparticles bombarded with C60 and Au400. International Journal of Mass Spectrometry, 2013, 334, 43-48.	0.7	18
44	Trace elemental analysis by heavy ion induced x-ray emission. Analytical Chemistry, 1976, 48, 2124-2129.	3.2	17
45	Multiple secondary ion emission from keV massive gold projectile impacts. International Journal of Mass Spectrometry, 2005, 241, 57-61.	0.7	17
46	Influence of massive projectile size and energy on secondary ion yields from organic surfaces. Applied Surface Science, 2006, 252, 6529-6532.	3.1	17
47	Molecular ion emission from single large cluster impacts. Applied Surface Science, 2006, 252, 6490-6493.	3.1	17
48	Examination of Nanoparticles via Single Large Cluster Impacts. Nano Letters, 2008, 8, 1076-1080.	4.5	17
49	Measuring the internal energies of species emitted from hypervelocity nanoprojectile impacts on surfaces using recalibrated benzylpyridinium probe ions. Journal of Chemical Physics, 2013, 138, 214301.	1.2	17
50	Single impacts of keV fullerene ions on free standing graphene: Emission of ions and electrons from confined volume. Journal of Chemical Physics, 2015, 143, 164302.	1.2	17
51	Hypervelocity nanoparticle impacts on free-standing graphene: A sui generis mode of sputtering. Journal of Chemical Physics, 2015, 142, 044308.	1.2	17
52	Testing Molecular Homogeneity at the Nanoscale with Massive Cluster Secondary Ion Mass Spectrometry. Analytical Chemistry, 2016, 88, 7639-7646.	3.2	17
53	On the determination of sulfur by charged particle activation analysis. Journal of Radioanalytical Chemistry, 1973, 16, 375-383.	0.5	16
54	A new experimental method for determining secondary ion yields from surfaces bombarded by complex neterogeneous ions. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1990, 8, 2265-2268.	0.9	16

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55	Surface structure investigations using plasma desorption mass spectrometry and coincidence counting. International Journal of Mass Spectrometry and Ion Processes, 1993, 128, 133-141.	1.9	16
56	Negative secondary ion emission from NaBF4: comparison of atomic and polyatomic projectiles at different impact energies. Journal of Mass Spectrometry, 1999, 34, 554-562.	0.7	16
57	Label Free Particle-by-Particle Quantification of DNA Loading on Sorted Gold Nanostars. Analytical Chemistry, 2019, 91, 5566-5572.	3.2	16
58	Quantitative Label-Free Characterization of Avidin–Biotin Assemblies on Silanized Glass. Analytical Chemistry, 2011, 83, 7173-7178.	3.2	15
59	High energy heavy-ion induced X-ray emission analysis. Nuclear Instruments & Methods, 1977, 142, 111-119.	1.2	14
60	On the origin of hydrogen clusters produced by particle induced desorption. Journal of Chemical Physics, 1988, 89, 6708-6712.	1.2	14
61	Characterization of Photooxidized Self-Assembled Monolayers and Bilayers by Spontaneous Desorption Mass Spectrometry. Analytical Chemistry, 2000, 72, 5973-5980.	3.2	14
62	Surface Mass Spectrometry at the Submicrometer Scale. Langmuir, 2002, 18, 8836-8840.	1.6	14
63	Prompt in situ emission of gold adducts from single impacts of large gold clusters on organics solids. International Journal of Mass Spectrometry, 2007, 263, 298-303.	0.7	14
64	A rapid method for assaying sulfur using proton activation analysis. Nuclear Instruments & Methods, 1972, 99, 461-467.	1,2	13
65	Charged particle activation analysis coupled with X-ray counting. Journal of Radioanalytical Chemistry, 1973, 16, 385-394.	0.5	13
66	High energy chemistry caused by fast ion-solid interactions. Nuclear Instruments & Methods in Physics Research B, 1995, 96, 530-535.	0.6	13
67	Matrix Effects on the Fragmentation of Vitamin B12 in Plasma Desorption Mass Spectrometry. Rapid Communications in Mass Spectrometry, 1997, 11, 143-147.	0.7	13
68	Secondary ion emission from keV energy atomic and polyatomic projectile impacts on sodium iodate. International Journal of Mass Spectrometry, 2000, 197, 149-161.	0.7	13
69	SIMS of Organic Anions Adsorbed onto an Aminoethanethiol Self-Assembled Monolayer:Â An Approach for Enhanced Secondary Ion Emission. Analytical Chemistry, 2000, 72, 2618-2626.	3.2	13
70	Cluster secondary ion mass spectrometry: an insight into "super-efficient―collision cascades. Applied Surface Science, 2004, 231-232, 54-58.	3.1	13
71	Molecular Identification of Individual Nano-Objects. Analytical Chemistry, 2009, 81, 7527-7531.	3.2	13
72	Fluoropolymer-diluted small molecule organic semiconductors with extreme thermal stability. Applied Physics Letters, 2018, 113, .	1,5	13

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73	Nanoprojectile Secondary Ion Mass Spectrometry for Analysis of Extracellular Vesicles. Analytical Chemistry, 2021, 93, 7481-7490.	3.2	13
74	Nanoparticle-Enabled Multiplexed Electrochemical Immunoassay for Detection of Surface Proteins on Extracellular Vesicles. ACS Applied Materials & Interfaces, 2021, 13, 52321-52332.	4.0	13
75	Determination of zinc and nickel by charged particle activation analysis. Analytical Chemistry, 1973, 45, 2111-2115.	3.2	12
76	Coincidence counting for the study of hydrocarbon ion desorption in plasma desorption mass spectrometry. Journal of Chemical Physics, 1992, 96, 3206-3210.	1.2	12
77	Multiplicity analysis: a study of secondary particle distribution and correlation. Surface Science, 1998, 408, 28-42.	0.8	12
78	Massive clusters: Secondary emission from qkeV to qMeV. New emission processes? New SIMS probe?. Surface and Interface Analysis, 2011, 43, 62-65.	0.8	12
79	Advanced photoresist technologies by intricate molecular brush architectures: Diblock brush terpolymerâ€based positiveâ€tone photoresist materials. Journal of Polymer Science Part A, 2015, 53, 193-199.	2.5	12
80	Alpha activation of calcium and its possible use for analysis. Journal of Radioanalytical Chemistry, 1971, 7, 319-327.	0.5	11
81	On the application of charged particle activation analysis to the trace characterization of semiconductor materials. Journal of Radioanalytical Chemistry, 1974, 19, 89-108.	0.5	11
82	Nuclear and atomic activation with heavy ion beams. Journal of Radioanalytical Chemistry, 1978, 43, 559-573.	0.5	11
83	Studies in heavy ion activation analysis I. on the selection of activation reactions. Journal of Radioanalytical Chemistry, 1979, 53, 173-180.	0.5	11
84	Emission of molecular fragments synthesized in hypervelocity nanoparticle impacts. International Journal of Mass Spectrometry, 2008, 275, 86-90.	0.7	11
85	Characterization and quantification of biological micropatterns using cluster SIMS. Surface and Interface Analysis, 2011, 43, 555-558.	0.8	11
86	Electrochemical release of hepatocyte-on-hydrogel microstructures from ITO substrates. Analytical and Bioanalytical Chemistry, 2012, 402, 1847-1856.	1.9	11
87	Metal-assisted SIMS with hypervelocity gold cluster projectiles. International Journal of Mass Spectrometry, 2013, 343-344, 28-36.	0.7	11
88	The collision of a hypervelocity massive projectile with free-standing graphene: Investigation of secondary ion emission and projectile fragmentation. Journal of Chemical Physics, 2017, 146, 054305.	1.2	11
89	Molecular Colocalization Using Massive Gold Cluster Secondary Ion Mass Spectrometry. Analytical Chemistry, 2018, 90, 12692-12697.	3.2	11
90	Determination of iron in glass and cobalt via charged particle activation analysis. Analytical Chemistry, 1974, 46, 655-658.	3.2	10

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91	Activation analysis opportunities using a $5\hat{A}\cdot1012$ to $5\hat{A}\cdot1013$ n/sec 14 MeV generator. Journal of Radioanalytical Chemistry, 1977, 37, 307-312.	0.5	10
92	On the determination of carbon and oxygen impurities in silicon by 3He activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1984, 81, 125-129.	0.7	10
93	Fingerprinting of polymer surfaces with Cfâ€252 particle desorption mass spectrometry. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1988, 6, 946-949.	0.9	10
94	A coincidence counting study of polyatomic ion induced sputtering. Journal of Chemical Physics, 1992, 96, 8171-8176.	1.2	10
95	Carbon-cluster formation from polymers caused by MeV-ion impacts and keV-cluster-ion impacts. Physical Review A, 1999, 59, 4470-4474.	1.0	10
96	Au-analyte adducts resulting from single massive gold cluster impacts. Applied Surface Science, 2006, 252, 6558-6561.	3.1	10
97	Characteristics of positive and negative secondary ions emitted from Au ₃ ⁺ and Au ₄₀₀ ⁺⁴ impacts. Surface and Interface Analysis, 2013, 45, 134-137.	0.8	10
98	Bottom-up/top-down, high-resolution, high-throughput lithography using vertically assembled block bottle brush polymers. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2013, 12, 043006.	1.0	10
99	Mass Spectrometry of Nanoparticles is Different. Journal of the American Society for Mass Spectrometry, 2015, 26, 1259-1265.	1.2	10
100	Hypervelocity cluster ion impacts on free standing graphene: Experiment, theory, and applications. Journal of Chemical Physics, 2019, 150, 160901.	1.2	10
101	Topological Design of Highly Anisotropic Aligned Hole Transporting Molecular Bottlebrushes for Solution-Processed OLEDs. Journal of the American Chemical Society, 2022, 144, 8084-8095.	6.6	10
102	Exit conditions for secondary ion emission induced by keV cluster bombardment. Nuclear Instruments & Methods in Physics Research B, 1993, 82, 317-322.	0.6	9
103	Solid-state luminescence: Probe for ion-solid interactions. Physical Review B, 1995, 51, 7373-7376.	1.1	9
104	Coincidental emission of molecular ions from keV carbon cluster impacts. International Journal of Mass Spectrometry, 2004, 238, 59-64.	0.7	9
105	Characterization of surface structure by cluster coincidental ion mass spectrometry. Applied Surface Science, 2004, 231-232, 106-112.	3.1	9
106	Bidirectional Ion Emission from Massive Gold Cluster Impacts on Nanometric Carbon Foils. Journal of Physical Chemistry C, 2012, 116, 8138-8144.	1.5	9
107	Advances in accelerator based analysis techniques. Journal of Radioanalytical Chemistry, 1981, 64, 195-212.	0.5	8
108	On the determination of phosphorus via charged particle activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1985, 91, 173-178.	0.7	8

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109	252Cf-particle desorption mass spectrometry in a depth profiling mode. Nuclear Instruments & Methods in Physics Research B, 1988, 34, 89-96.	0.6	8
110	Particle desorption mass spectrometry of Yî—Baî—Cuî—O superconductors. International Journal of Mass Spectrometry and Ion Processes, 1989, 91, R5-R11.	1.9	8
111	Spontaneous desorption: field assisted ion induced desorption mass spectrometry. International Journal of Mass Spectrometry and Ion Processes, 1990, 97, 311-324.	1.9	8
112	Sputtering of Tetrafluoro- and Tetraphenylborate Anions Adsorbed to an Amine-Terminated Self-Assembled Monolayer Surface. Journal of Physical Chemistry B, 1999, 103, 7929-7934.	1.2	8
113	Determination of the metastable dissociation pathways for chromium/oxygen cluster ions sputtered from potassium chromate and dichromate using the ion-neutral correlation method. International Journal of Mass Spectrometry, 2000, 203, 59-69.	0.7	8
114	Layer-by-layer characterization of ultrathin films with secondary ion mass spectrometry. Applied Surface Science, 2004, 231-232, 328-331.	3.1	8
115	Photon, Electron, and Secondary Ion Emission from Single C ₆₀ keV Impacts. Journal of Physical Chemistry Letters, 2010, 1, 3510-3513.	2.1	8
116	Electron Emission from Hypervelocity C ₆₀ Impacts. Journal of Physical Chemistry C, 2010, 114, 17191-17196.	1.5	8
117	Ejection-ionization of molecules from free standing graphene. Journal of Chemical Physics, 2017, 146, 084308.	1.2	8
118	On the possibility of using an electromagnetic radioisotope separator in conjunction with charged-particle and photon-activation analysis. Talanta, 1968, 15, 883-885.	2.9	7
119	Micro and surface analysis with fast heavy ions. Analytica Chimica Acta, 1987, 195, 163-172.	2.6	7
120	A brief review of the determination of cadmium by prompt gamma-ray neutron activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1991, 152, 497-506.	0.7	7
121	A spontaneous desorptionâ€based polyatomic ion source. Review of Scientific Instruments, 1993, 64, 1748-1753.	0.6	7
122	A preliminary screening technique for selected metals at waste sites. Journal of Radioanalytical and Nuclear Chemistry, 1995, 192, 275-280.	0.7	7
123	Speciation of Sodium Nitrate and Sodium Nitrite Using Kiloelectronvolt Energy Atomic and Polyatomic and Megaelectronvolt Energy Atomic Projectiles with Secondary Ion Mass Spectrometry. Analytical Chemistry, 2000, 72, 2468-2474.	3.2	7
124	Realâ€time localization of single C ₆₀ impacts with correlated secondary ion detection. Surface and Interface Analysis, 2011, 43, 484-487.	0.8	7
125	On the surface mapping using individual cluster impacts. Nuclear Instruments & Methods in Physics Research B, 2012, 273, 270-273.	0.6	7
126	Charged particle activation analysis applied to the detection of heavy elements. Journal of Radioanalytical Chemistry, 1973, 16, 413-419.	0.5	6

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127	Neutron activation analysis of flints from the edwards formation. Journal of Radioanalytical Chemistry, 1979, 52, 101-110.	0.5	6
128	Studies in heavy ion activation analysis. Journal of Radioanalytical Chemistry, 1979, 54, 281-288.	0.5	6
129	Studies in heavy ion activation analysis. Journal of Radioanalytical Chemistry, 1980, 60, 255-260.	0.5	6
130	Radioactive implant induced X-ray emission. Nuclear Instruments & Methods in Physics Research, 1982, 193, 21-25.	0.9	6
131	Studies in heavy ion activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1985, 90, 341-348.	0.7	6
132	Design and performance evaluation of a miniaturized particle desorption mass spectrometer. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 1988, 273, 203-210.	0.7	6
133	Surface analysis with keV polyatomic projectiles. Nuclear Instruments & Methods in Physics Research B, 1991, 56-57, 361-364.	0.6	6
134	Plasma desorption mass spectrometry with coincidence counting for the analysis of polymer surfaces. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1991, 9, 1300-1306.	0.9	6
135	Diffusion of lithium-6 isotopes in lithium aluminate ceramics using neutron depth profiling. Journal of Nuclear Materials, 1993, 203, 43-49.	1.3	6
136	Sublinear effect in light emission from cesium iodide bombarded by keV polyatomic projectiles. Nuclear Instruments & Methods in Physics Research B, 1998, 134, 352-359.	0.6	6
137	Organic SIMS with single massive gold projectile: Ion yield enhancement by silver metallization. Applied Surface Science, 2006, 252, 6644-6647.	3.1	6
138	Photon emission from massive projectile impacts on solids. Surface and Interface Analysis, 2011, 43, 53-57.	0.8	6
139	2D AlB2 flakes for epitaxial thin film growth. Journal of Materials Research, 2018, 33, 2318-2326.	1.2	6
140	Trace determination of zirconium using charged particle activation. Journal of Radioanalytical Chemistry, 1974, 22, 139-145.	0.5	5
141	Spatially resolved heavy ion induced desorption mass spectrometry. International Journal of Mass Spectrometry and Ion Physics, 1983, 53, 331-334.	1.3	5
142	Particle induced desorption mass spectrometry in a microscopic mode. Analytical Chemistry, 1986, 58, 1686-1690.	3.2	5
143	Ion-induced desorption in insulators by Hydrogen cluster impact up to 600 KeV. Radiation Effects, 1986, 99, 213-226.	0.4	5
144	X-ray photoelectron spectroscopy and Rutherford backscattering spectrometry study of anion incorporation in anodically grown films. Thin Solid Films, 1988, 167, 245-254.	0.8	5

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145	Cf-252 particle desorption mass spectrometry of photo-oxidized polystyrene. Surface and Interface Analysis, 1990, 15, 503-508.	0.8	5
146	Fragment ion formation fromn-alkanes and cycloalkanes by plasma desorption. Organic Mass Spectrometry, 1994, 29, 679-683.	1.3	5
147	The use of coincidence counting mass spectrometry to study the emission and metastable dissociation of cluster ions. Nuclear Instruments & Methods in Physics Research B, 1996, 112, 68-71.	0.6	5
148	Secondary cluster ion distributions produced by MeV ion impacts on Group IIA oxides and nitrates. International Journal of Mass Spectrometry and Ion Processes, 1996, 155, 89-97.	1.9	5
149	An old-new tool for nuclear analysis: Time-of-Flight spectrometry. Journal of Radioanalytical and Nuclear Chemistry, 1997, 215, 23-30.	0.7	5
150	Recoiled ions from polyatomic cluster impacts on organic and inorganic targets. Nuclear Instruments & Methods in Physics Research B, 1998, 142, 606-611.	0.6	5
151	Nanodomain analysis via coincidence ion mass spectrometry. Applied Surface Science, 2004, 231-232, 113-116.	3.1	5
152	SIMS methodology for probing the fate and dispersion of catalytically active molecules. International Journal of Mass Spectrometry, 2014, 370, 107-113.	0.7	5
153	Characterization of individual free-standing nano-objects by cluster SIMS in transmission. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2016, 34, 03H117.	0.6	5
154	"Trampoline―ejection of organic molecules from graphene and graphite via keV cluster ions impacts. Journal of Chemical Physics, 2018, 148, 144309.	1.2	5
155	Understanding photoacid generator distribution at the nanoscale using massive cluster secondary ion mass spectrometry. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2019, 18, 1.	1.0	5
156	Microanalysis of "biometallic―compounds using nuclear and atomic activation. Journal of Radioanalytical Chemistry, 1979, 52, 117-126.	0.5	4
157	Rutherford Backscattering with Heavy Ions. IEEE Transactions on Nuclear Science, 1981, 28, 1831-1833.	1.2	4
158	Studies in heavy ion activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1985, 88, 369-377.	0.7	4
159	Trace determination of lead by helium-4 activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 1987, 119, 81-86.	0.7	4
160	Advances in nuclear analysis methods. Analyst, The, 1989, 114, 269.	1.7	4
161	Surface characterization of chemically modified chrysotile asbestos by particle-induced desorption mass spectrometry. Surface and Interface Analysis, 1990, 15, 651-658.	0.8	4
162	New approaches for neutron depth profiling. Journal of Radioanalytical and Nuclear Chemistry, 1994, 180, 255-262.	0.7	4

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163	A mass spectrometric method for probing surface structure. Vacuum, 1995, 46, 1227-1230.	1.6	4
164	Secondary cluster ion emission from megaelectron volts ion impacts on NaBF4. 1. Ion decay fractions and dissociation pathways. International Journal of Mass Spectrometry, 2000, 202, 111-119.	0.7	4
165	Secondary ion yield improvements for phosphated and sulfated molecules using substrate-enhanced time-of-flight secondary ion mass spectrometry. International Journal of Mass Spectrometry, 2001, 209, 113-124.	0.7	4
166	Influence of constituent mass on secondary ion yield enhancements from polyatomic ion impacts on aminoethanethiol self-assembled monolayer surfaces. Rapid Communications in Mass Spectrometry, 2001, 15, 370-372.	0.7	4
167	A novel approach for coincidence ion mass spectrometry. Analytical and Bioanalytical Chemistry, 2002, 373, 609-611.	1.9	4
168	Surface characterization of biological nanodomains using NPâ€ToFâ€SIMS. Surface and Interface Analysis, 2013, 45, 294-297.	0.8	4
169	HYDROGEN IONS EMISSION UNDER FAST CHARGED PARTICLES : THE BEGINNING OF THE DESORPTION PROCESS. Journal De Physique Colloque, 1989, 50, C2-79-C2-84.	0.2	4
170	Nanoscale molecular analysis of photoresist films with massive cluster secondary-ion mass spectrometry. Journal of Micro/ Nanolithography, MEMS, and MOEMS, 2019, 18, 1.	1.0	4
171	Nanoprojectile Secondary Ion Mass Spectrometry for Nanometrology of Nanoparticles and Their Interfaces. Analytical Chemistry, 2022, 94, 7868-7876.	3.2	4
172	Studies in heavy ion activation analysis. Journal of Radioanalytical Chemistry, 1980, 60, 261-265.	0.5	3
173	The unusual structure of tungsten-doped electrochemically-grown alumina films detected by MeV ion scattering. Journal of the Chemical Society Chemical Communications, 1984, , 1560.	2.0	3
174	Application of particle desorption mass spectrometry to the characterization of minerals. Analytical Chemistry, 1986, 58, 2126-2129.	3.2	3
175	Surface characterization of a National Bureau of Standards glass reference material by californium-252 particle desorption mass spectrometry. Analytical Chemistry, 1988, 60, 1944-1947.	3.2	3
176	Studies in neutron depth profiling. Journal of Radioanalytical and Nuclear Chemistry, 1993, 167, 111-119.	0.7	3
177	Primary ion production from various gases in spontaneous desorption. International Journal of Mass Spectrometry and Ion Processes, 1993, 128, 107-113.	1.9	3
178	Coincidence counting analysis of secondary ions emitted from a phenylalanine target under multicharged MeV carbon bombardment. International Journal of Mass Spectrometry and Ion Processes, 1994, 136, 107-117.	1.9	3
179	Luminescence of self-trapped excitons induced by single keV ion bombardment. Nuclear Instruments & Methods in Physics Research B, 1995, 100, 383-388.	0.6	3
180	A plasma desorption mass spectrometry study of cluster ion formation from group IIA nitrates. Nuclear Instruments & Methods in Physics Research B, 1996, 112, 55-58.	0.6	3

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181	Examination of individual nanoparticles with cluster SIMS. Surface and Interface Analysis, 2011, 43, 547-550.	0.8	3
182	Statistics of electron and ion emission from single massive cluster impacts. Surface and Interface Analysis, 2011, 43, 49-52.	0.8	3
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